

2-Propanol
CMOS

(iso-propyl alcohol)



Material No.: 9059-08
Batch No.: 0000255777
Manufactured Date: 2020/03/09
Retest Date: 2025/03/08
Revision No: 1

Certificate of Analysis

| Test | Specification | Result |
|---|---------------|--------|
| Assay (CH ₃ CHOHCH ₃) | >= 99.5 % | 100.0 |
| Color (APHA) | <= 10 | < 5 |
| Residue after Evaporation | <= 4 ppm | < 1 |
| Solubility in H ₂ O | Passes Test | PT |
| Water (H ₂ O)(by Karl Fischer titrn) | <= 0.05 % | 0.01 |
| Acidity (µeq/g) | <= 0.2 | 0.1 |
| Alkalinity (µeq/g) | <= 0.1 | < 0.1 |
| Chloride (Cl) | <= 0.1 ppm | < 0.1 |
| Phosphate (PO ₄) | <= 0.3 ppm | < 0.3 |
| Trace Impurities – Aluminum (Al) | <= 50.0 ppb | < 5.0 |
| Arsenic and Antimony (as As) | <= 10 ppb | < 10 |
| Trace Impurities – Barium (Ba) | <= 20.0 ppb | < 1.0 |
| Trace Impurities – Beryllium (Be) | <= 100.0 ppb | < 1.0 |
| Trace Impurities – Bismuth (Bi) | <= 100.0 ppb | < 10.0 |
| Trace Impurities – Boron (B) | <= 10.0 ppb | < 5.0 |
| Trace Impurities – Cadmium (Cd) | <= 20.0 ppb | < 1.0 |
| Trace Impurities – Calcium (Ca) | <= 50.0 ppb | < 1.0 |
| Trace Impurities – Chromium (Cr) | <= 20.0 ppb | < 1.0 |
| Trace Impurities – Cobalt (Co) | <= 20.0 ppb | < 1.0 |
| Trace Impurities – Copper (Cu) | <= 10.0 ppb | < 1.0 |
| Trace Impurities – Gallium (Ga) | <= 50.0 ppb | < 1.0 |
| Trace Impurities – Germanium (Ge) | <= 50.0 ppb | < 10.0 |
| Trace Impurities – Gold (Au) | <= 20.0 ppb | < 5.0 |
| Heavy Metals (as Pb) | <= 200 ppb | < 100 |

For questions on this Certificate of Analysis please contact Technical Services at 855.282.6867 or +1.610.386.1700
Avantor Performance Materials, LLC
100 Matsonford Rd, Suite 200, Radnor, PA 19087. U.S.A. Phone: 610.386.1700

| Test | Specification | Result |
|---|---------------|--------|
| Trace Impurities – Iron (Fe) | <= 50.0 ppb | < 1.0 |
| Trace Impurities – Lead (Pb) | <= 20.0 ppb | < 10.0 |
| Trace Impurities – Lithium (Li) | <= 50.0 ppb | < 1.0 |
| Trace Impurities – Magnesium (Mg) | <= 20.0 ppb | < 1.0 |
| Trace Impurities – Manganese (Mn) | <= 15.0 ppb | < 1.0 |
| Trace Impurities – Molybdenum (Mo) | <= 100.0 ppb | < 5.0 |
| Trace Impurities – Nickel (Ni) | <= 10.0 ppb | < 5.0 |
| Trace Impurities – Niobium (Nb) | <= 100.0 ppb | < 1.0 |
| Trace Impurities – Potassium (K) | <= 100.0 ppb | < 10.0 |
| Trace Impurities – Silicon (Si) | <= 50.0 ppb | < 10.0 |
| Trace Impurities – Silver (Ag) | <= 20.0 ppb | < 1.0 |
| Trace Impurities – Sodium (Na) | <= 100.0 ppb | < 5.0 |
| Trace Impurities – Strontium (Sr) | <= 20.0 ppb | < 1.0 |
| Trace Impurities – Tantalum (Ta) | <= 100.0 ppb | < 5.0 |
| Trace Impurities – Thallium (Tl) | <= 10.0 ppb | < 5.0 |
| Trace Impurities – Tin (Sn) | <= 100.0 ppb | < 10.0 |
| Trace Impurities – Titanium (Ti) | <= 20.0 ppb | < 1.0 |
| Trace Impurities – Vanadium (V) | <= 100.0 ppb | < 1.0 |
| Trace Impurities – Zinc (Zn) | <= 50.0 ppb | < 1.0 |
| Trace Impurities – Zirconium (Zr) | <= 100.0 ppb | < 1.0 |
| Particle Count at point of fill – 0.5 µm and greater (Rion KS42AF) | <= 150 par/ml | 5 |
| Particle Count at point of fill – 1.0 µm and greater (Rion KS42AF) | <= 25 par/ml | 2 |

For Microelectronic Use

Country of Origin: US
Packaging Site: Paris Mfg Ctr & DC



Jamie Ethier
Vice President Global Quality